

Notice of References Cited	Application/Control No. 10/824,715	Applicant(s)/Patent Under Reexamination BORRELLI ET AL.	
	Examiner Christopher B. Shin	Art Unit 2181	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0111537	06-2004	Connor et al.	710/006
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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